Attorney Docket Number	1011-67627-01
Application Number	10/781,031
Filing Date	February 17, 2004
First Named Inventor	Rajski
Art Unit	2193
Examiner Name	David H. Malzahn

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Examiner's Initials*	Cite No. (optional)	Number	Issue or Publication Date	Name of Applicant or Patentee
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EXAMINER SIGNATURE: D. H. Malzahn	DATE CONSIDERED: 4/12/06

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PMB:iar 01/10/06 1011-67627-01

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